Expedited Procedure—Group 2877 **PATENT**

S/N 09/111,978

TES PATENT AND TRADEMARK OFFICE

Applicant:

Leonard H. Bieman

Serial No.:

09/111,978

Filed: Title:

July 8, 1998

Group Art Unit: 2877 Docket: 139.045USR

SCANNING PHASE MEASURING METHOD AND SYSTEM FOR AN

Examiner: Hoa Q. Pham

OBJECT AT A VISION STATION

AMENDMENT AND RESPONSE UNDER 37 CFR § 1.116

Commissioner for Patents Washington, D.C. 20231

Applicant has reviewed the Final Office Action mailed June 22, 2001. Please and above-identified patent application as follows.

IN THE CLAIMS

Please amend claims 30 and 60 as follows: (Status of all claims after current Amendment, with underlining and bracketing showing changes from originally issued claims.) A clean copy of the pending claims is attached as an appendix.

1. [Amended Once] A method for high speed, scanning phase measuring of an object at a vision station to develop physical information associated with the object, the method comprising the steps of:

projecting a pattern of imagable electromagnetic radiation with at least one projector; moving the object relative to the at least one projector at a substantially constant velocity at the vision station so as to scan the projected pattern of electromagnetic radiation across a surface of the object to generate an imagable electromagnetic radiation signal;

receiving the imagable electromagnetic radiation signal from the surface of the object with a detector having a plurality of separate detector elements which are substantially uniformly spaced;

maintaining the at least one projector and the pattern of imagable electromagnetic radiation and the detector in a substantially fixed relation to each other;

measuring an amount of radiant energy in the received electromagnetic radiation signal